

ZXMN2F30FH 20V SOT23 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	R _{DS(on)} (Ω)	I _D (A)
20	0.045 @ V _{GS} = 4.5V	4.9
	0.065 @ V _{GS} = 2.5V	4.1

Description

This new generation Trench MOSFET from Zetex features low on-resistance achievable with low (2.5V) gate drive.

Features

- · Low on-resistance
- 2.5V gate drive capability
- SOT23 package

Applications

- Buck/Boost DC-DC Converters
- Load switching and SMPS
- Charging applications in portable equipment
- Motor Control
- LED Lighting

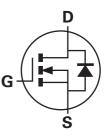
Ordering information

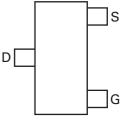
DEVICE	Reel size	Tape width	Quantity
	(inches)	(mm)	per reel
ZXMN2F30FHTA	7	8	3000

Device marking

KNC







Top view

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V _{DSS}	20	V
Gate source voltage	V _{GS}	±12	V
Continous Drain Current @ V_{GS} =4.5; T_A =25°C ^(b) @ V_{GS} =4.5; T_A =70°C ^(b) @ V_{GS} =4.5; T_A =25°C ^(a)	۱ _D	4.9 4.0 4.1	A A A
Pulsed drain current ^(c)	I _{DM}	22.6	A
Continuous source current (body diode) ^(b)	۱ _S	1.6	А
Pulsed source current (body diode) ^(c)	I _{SM}	22.6	А
Power dissipation at $T_A = 25^{\circ}C^{(a)}$	PD	0.96	W
Linear derating factor		7.6	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(b)}$	P _D	1.4	W
Linear derating factor		11.2	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{\Theta JA}$	131	°C/W
Junction to ambient ^(b)	$R_{\Theta JA}$	89	°C/W
Junction to Lead ^(d)	R _{⊖JL}	68	°C/W

NOTES:

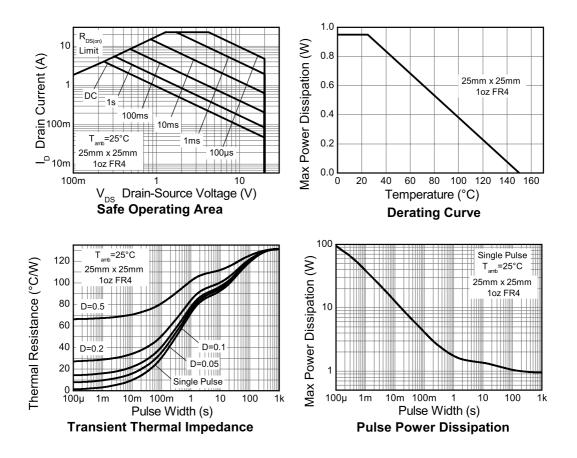
(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at ts 5 sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width 300μs - pulse width limited by maximum junction temperature.

(d) Thermal resistance from junction to solder-point (at the end of the drain lead).

Thermal characteristics



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static	1			•			
Drain-Source Breakdown Voltage	V _{(BR)DSS}	20			V	I _D = 250μA, V _{GS} =0V	
Zero Gate Voltage Drain Current	I _{DSS}			1	μA	V _{DS} = 20V, V _{GS} =0V	
Gate-Body Leakage	I _{GSS}			100	nA	$V_{GS}=\pm 12V, V_{DS}=0V$	
Gate-Source Threshold Voltage	V _{GS(th)}	0.6	0.9	1.5	V	I _D = 250μA, V _{DS} =V _{GS}	
Static Drain-Source	R _{DS(on)}			0.045	Ω	V _{GS} = 4.5V, I _D = 2.5A	
On-State Resistance ^(*)				0.065	Ω	V_{GS} = 2.5V, I_{D} = 2.0A	
Forward Transconductance ^{(*)(†)}	9 _{fs}		8.6		S	V _{DS} = 10V, I _D = 3A	
Dynamic ^(†)							
Input Capacitance	C _{iss}		452		pF		
Output Capacitance	C _{oss}		102		pF	− V _{DS} = 10V, V _{GS} =0V _ f=1MHz	
Reverse Transfer Capacitance	C _{rss}		58		pF		
Switching ^{(‡)(†)}	1			•			
Turn-On-Delay Time	t _{d(on)}		2.9		ns		
Rise Time	t _r		5.6		ns	− V _{DD} = 10V, V _{GS} = 4.5V − I _D = 1A	
Turn-Off Delay Time	t _{d(off)}		19.4		ns	R _G ≈ 6.0Ω	
Fall Time	t _f		10.2		ns		
Total Gate Charge	Qg		4.8		nC	V _{DS} = 10V, V _{GS} = 4.5V	
Gate-Source Charge	Q _{gs}		1		nC	I _D = 3.5A	
Gate Drain Charge	Q _{gd}		1.2		nC	1	
Source-drain diode			1	1		1	
Diode Forward Voltage ^(*)	V _{SD}		0.75	1.2	V	I _S = 1.25A, V _{GS} =0V	

Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

NOTES:

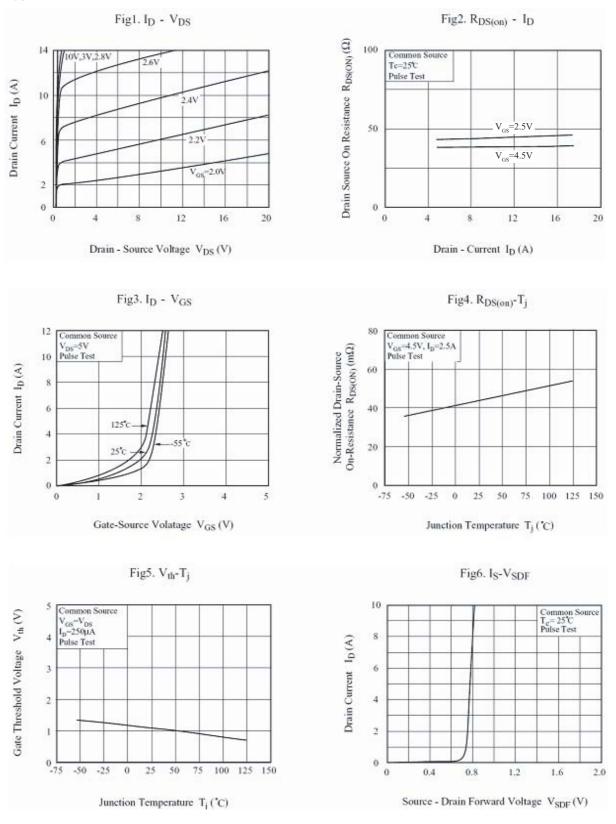
(*) Measured under pulsed conditions. Pulse width \leq 300 $\mu s;$ duty cycle $\leq\!\!2\%.$

(†) For design aid only, not subject to production testing.

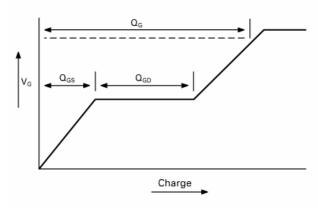
(‡) Switching characteristics are independent of operating junction temperature.

4

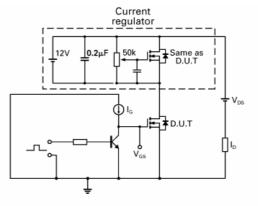
Typical characteristics



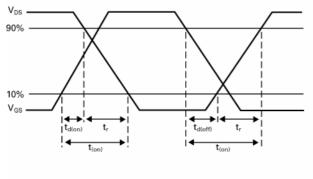
Test circuits



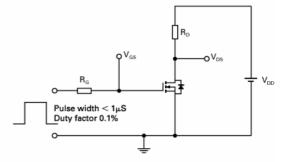
Basic gate charge waveform



Gate charge test circuit

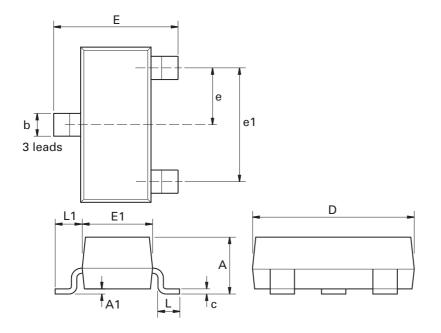


Switching time waveforms



Switching time test circuit

Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
А	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	E	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.20	0.003	0.008	L	0.25	0.60	0.0098	0.0236
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.037	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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